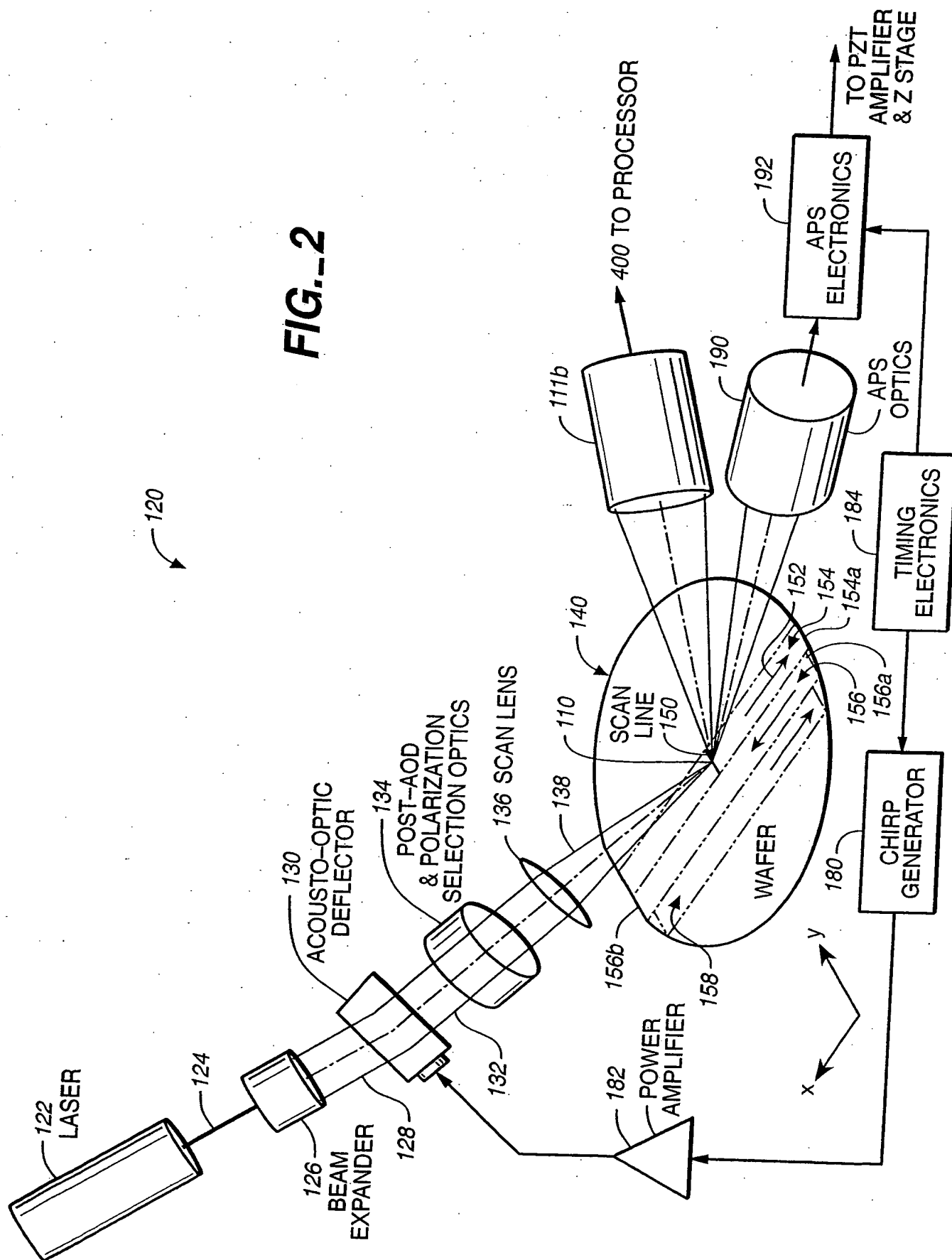
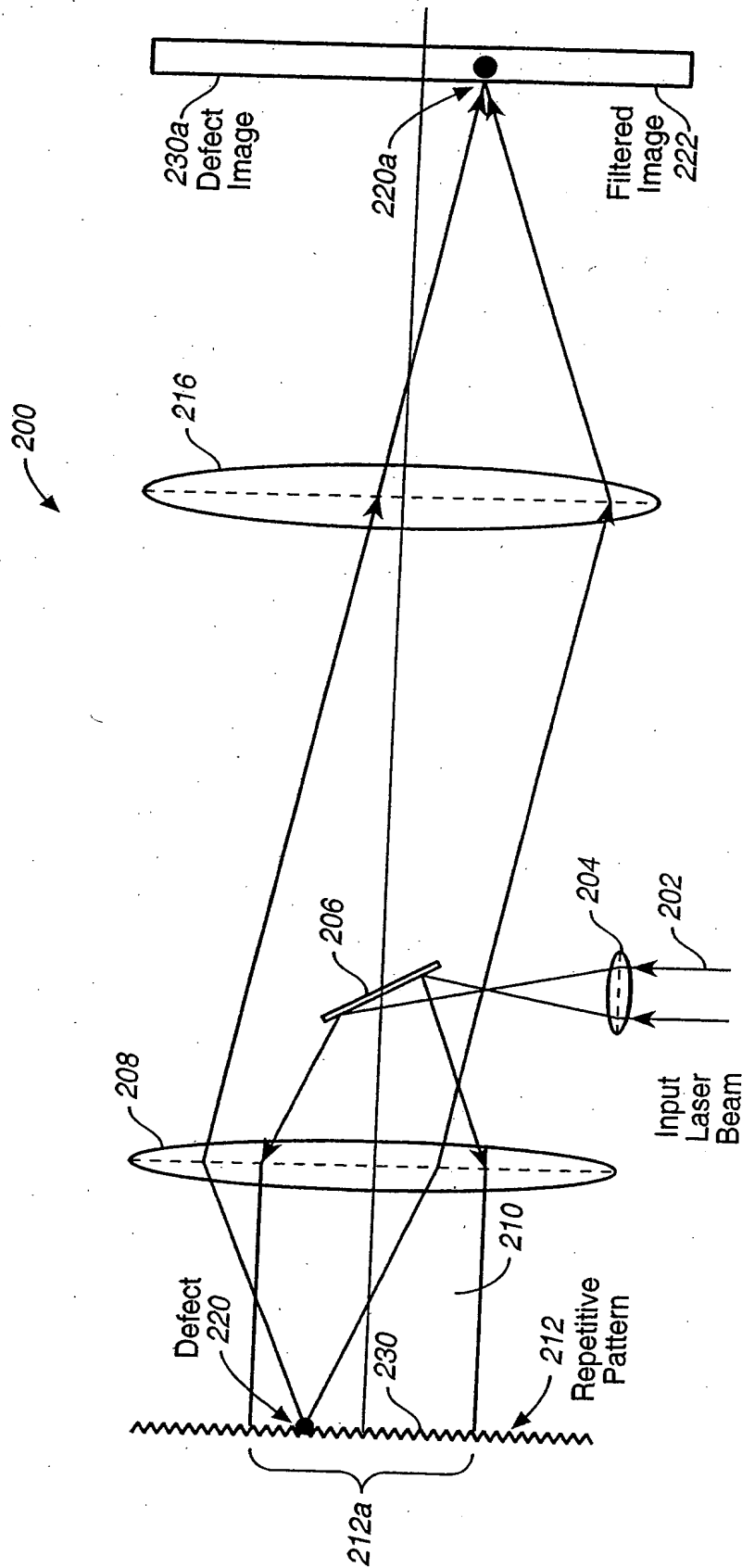


FIG. 1

FIG. 2



3 / 7



Optical Pattern Filtering Defect Detection

FIG. 3

4 / 7

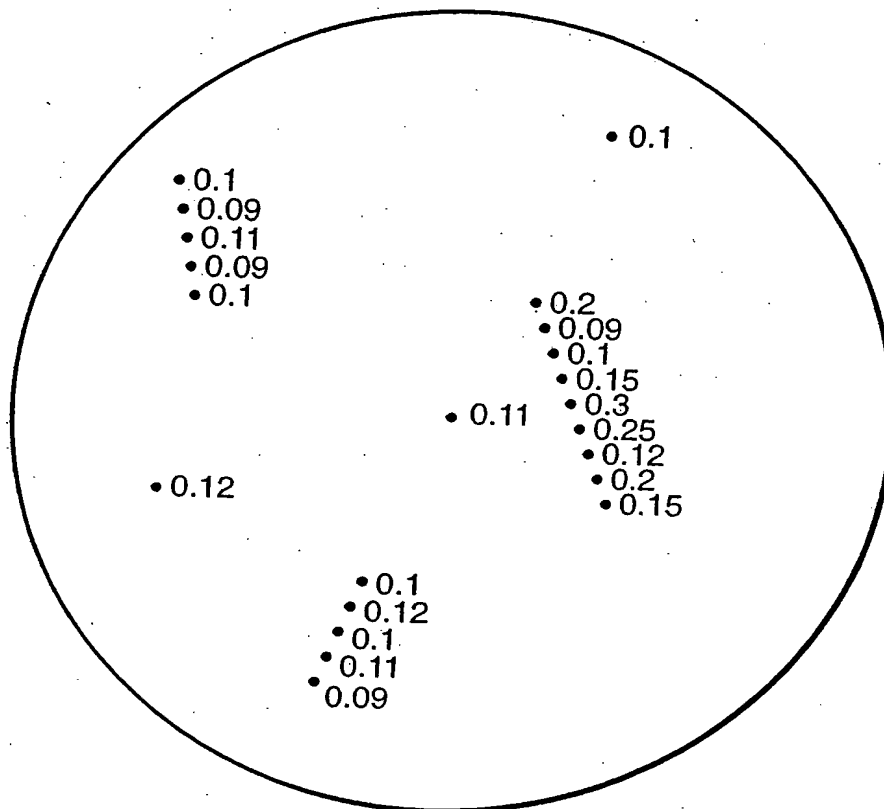


FIG. 4 Simulated Distribution of Defects After a Scan. Size Indicated in Microns

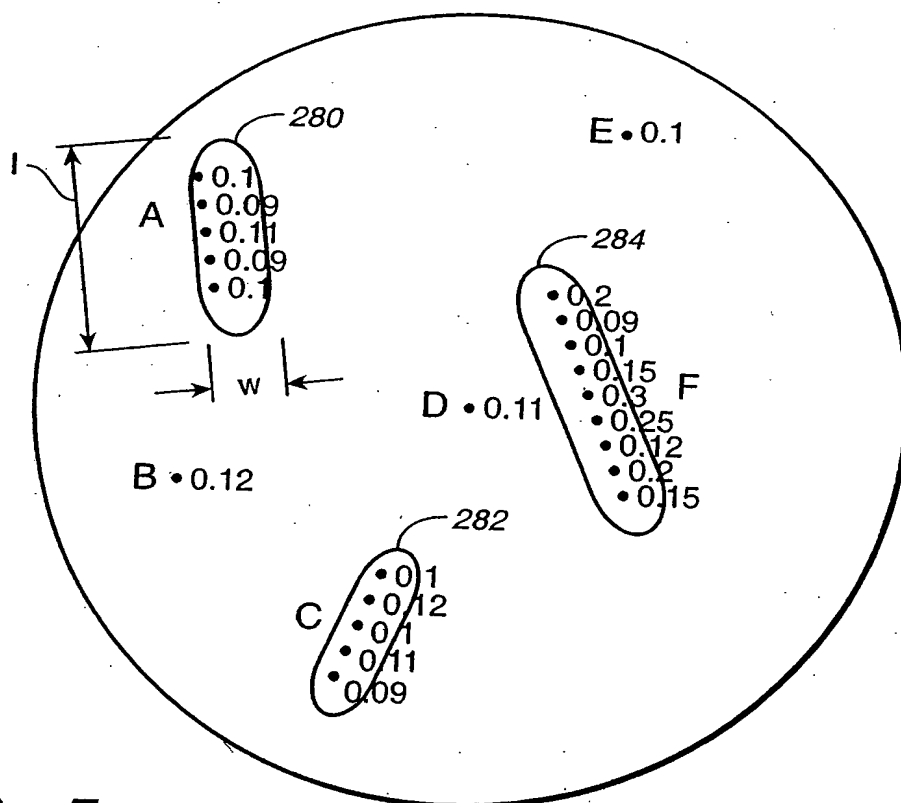
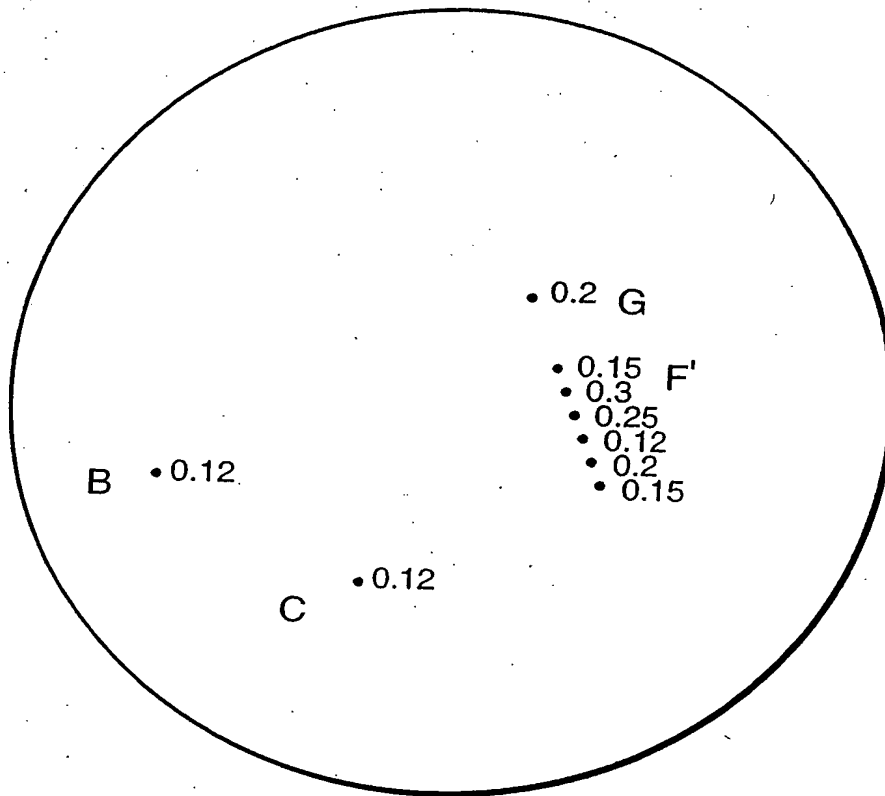


FIG. 5 Initial Clustering in Microscratch Algorithm



Final Output of the Microscratch Algorithm

FIG._6

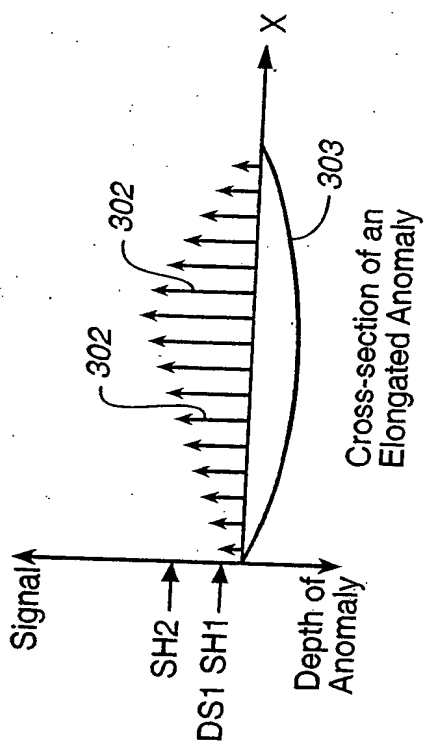


FIG. 7A

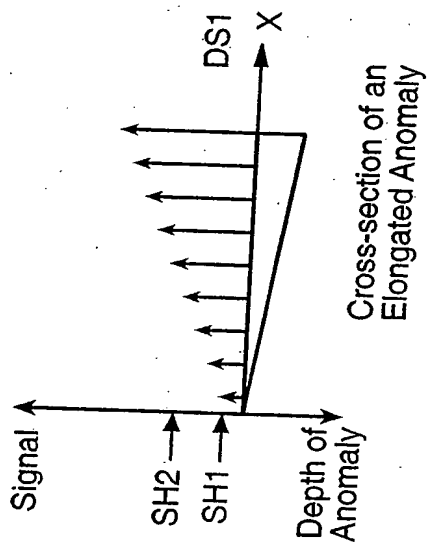


FIG. 7B

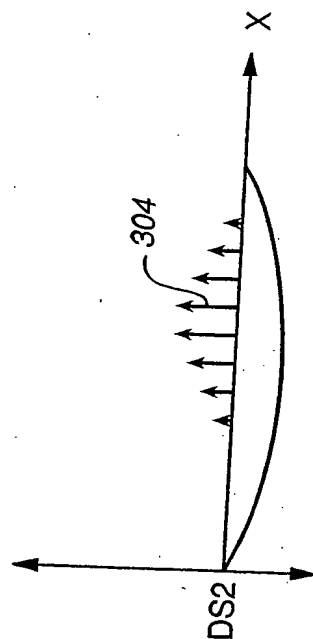


FIG. 8A

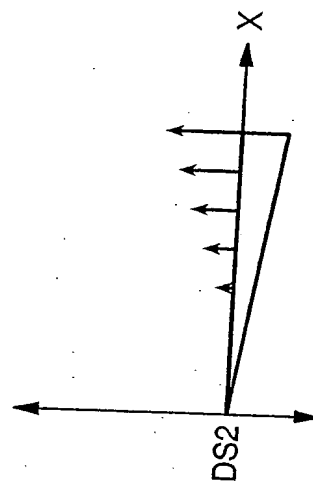


FIG. 8B

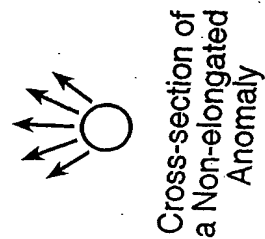


FIG. 9

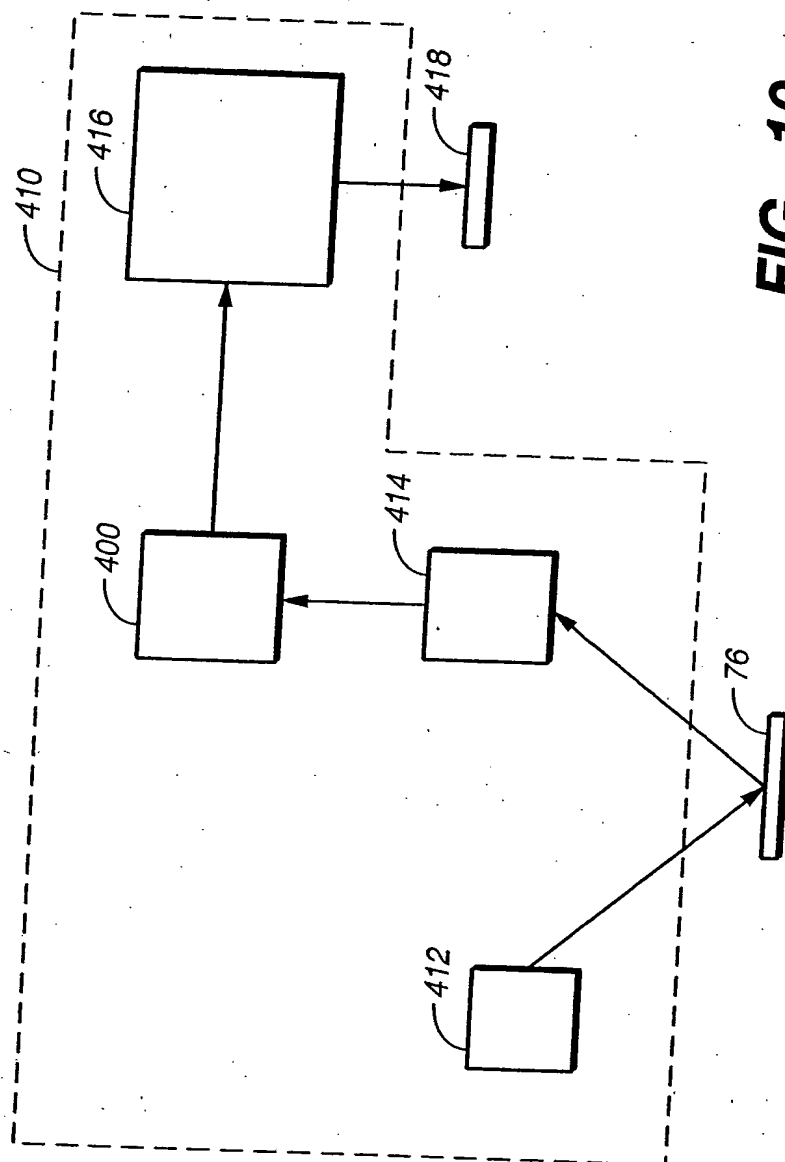


FIG. 10